

AMENDMENT TO THE ABSTRACT

Please replace paragraph 72, entitled Abstract, with the following paragraph:

~~An object of the~~ The present invention ~~is to provide~~ provides an ultimate analyzer which ~~can display~~ displays an element distribution image of an object ~~to be analyzed~~ with high contrast ~~to determine the positions of the element distribution with~~ and high accuracy, ~~and~~. [[a]] A scanning transmission electron microscope and a method of analyzing elements using the ultimate analyzer is also provided. ~~The present invention exists in an ultimate analyzer comprising~~ comprises a scattered electron beam detector for detecting an electron beam scattered by an object ~~to be analyzed~~; an electron spectrometer for energy dispersing an electron beam transmitted through the object ~~to be analyzed~~; an electron beam detector for detecting said dispersed electron beam; and a control unit for analyzing elements ~~of the object to be analyzed~~ based on an output signal of the electron beam detected by the electron beam detector and an output signal of the electron beam detected by the scattered electron beam detector. ~~Further, the present invention exists in a scanning transmission electron microscope comprising the above ultimate analyzer; an electron beam source; an electron beam scanning coil; a scattered electron beam detector; objective lenses; a focusing lens; a magnifying magnetic field lens; and a focus adjusting electromagnetic lens. Furthermore, the ultimate analyzer or the scanning transmission electron microscope may comprises a control unit which makes it possible that both of an image of element distribution and an STEM image detected and formed by the scatted electron beam detector are observed at a time in real time, and the image of element distribution is corrected by the STEM image detected and formed by the scattered electron beam detector.~~